# *EL2423D Die*

## Quad De-compensated, High Speed Operational Amplifiers

#### Absolute Maximum Ratings (TA = 25°C)

$v_s$	Voltage between V+ and V-	35V
$\Delta V_{IN}$	Differential Input Voltage	6V
IOP	Output Current, Peak	50 mA
Ioc	Output Current, Continuous	25 mA
$T_J$	Maximum Junction Temperature	175°C

#### Important Note:

For AC electrical characteristics, refer to the typical electrical table and performance curves in the package data sheet. These characteristics are guaranteed but not tested in die form. Unless otherwise noted, all tests are pulsed tests, therefore  $T_J = T_C = T_A$ .

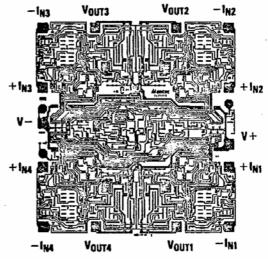
Test Level

Test Procedure

100% production tested in wafer form.

See remarks under Electrical Testing

in the General Die section.



DIE SIZE: 101 x 95 MILS

### DC Electrical Characteristics $V_S = \pm 15V$ , $R_L = 2 k\Omega$ , $T_A = 25^{\circ}C$

Parameter	Description	Min	Тур	Max	Test Level	Units
v <sub>os</sub>	Offset Voltage		1.0	6		mV
$I_B$	Bias Current		1.0	4		μΑ
Ios	Offset Current	-	0.5	2		μΑ
V <sub>CM</sub>	Common Mode Range	±10	±11		<b>*</b>	V
A <sub>VOL</sub>	Large Signal Voltage Gain (Note 1)	7k	10k		1	V/V
CMRR	Common-Mode Rejection Ratio (Note 2)	70	80		1	dB
v <sub>o</sub>	Output Voltage Swing	±11	±12			v
IO	Output Current	±25	±50	±85	A Company of the Comp	mA
IS	Supply Current		16	18	<b>经验</b>	mA
PSRR ·	Power Supply Rejection Ratio (Note 3)	70	80			ďΒ

Note 1:  $V_0 = \pm 10V$ .

Note 2: Two tests are performed.  $V_{CM} = 0V$  to +10V and  $V_{CM} = 0V$  to -10V.

Note 3: Two tests are performed. V + = +15V, and V - is changed from -5V to -15V. V - = -15V, and V + is changed from +5V to +15V.